

Design-for-destability-based external test and diagnosis of mesh-like network- on-a-chips

Raik, Jaan; Govind, Vineeth; **Ubar, Raimund-Johannes** IET computers and digital techniques 2009 / 5, p. 476-486 : ill
<http://dx.doi.org/10.1049/iet-cdt.2008.0096>

FPGA-based fault emulation of synchronous sequential circuits

Ellervee, Peeter; **Raik, Jaan**; **Tammemäe, Kalle**; **Ubar, Raimund-Johannes** IET computers and digital techniques 2007 / 2, p. 70-76 : ill <https://ieeexplore.ieee.org/abstract/document/1423822>

Test methods for crosstalk-induced delay and glitch faults in network-on-chip interconnects implementing asynchronous communication protocols

Bengtsson, Tomas; **Kumar, Shashi**; **Ubar, Raimund-Johannes**; **Jutman, Artur**; Peng, Zebo IET computers and digital techniques 2008 / 6, p. 445-460 https://www.diva-portal.org/smash/record.jsf?dswid=-5073&aq2=%5B%5B%5D%5D&c=39&af=%5B%5D&searchType=SIMPLE&sortOrder2=title_sort_asc&language=en&pid=diva2%3A290043&aq=%5B%5B%7B%22personId%22%3A%22authority-person%3A23389%22%7D%5D%5D&sf=all&aqe=%5B%5D&sortOrder=author_sort_asc&onlyFullText=false&noOfRows=50